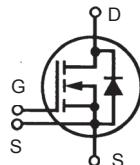


# HiPerFET™ Power MOSFETs

## IXFN 32N120

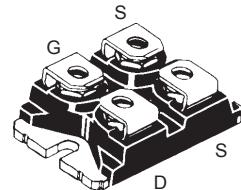
**V<sub>DSS</sub>** = 1200V  
**I<sub>D25</sub>** = 32A  
**R<sub>DS(on)</sub>** = 0.35Ω

N-Channel Enhancement Mode  
Avalanche Rated, High dv/dt, Low t<sub>rr</sub>



Symbol	Test Conditions	Maximum Ratings		
V <sub>DSS</sub>	T <sub>J</sub> = 25°C to 150°C	1200	V	
V <sub>DGR</sub>	T <sub>J</sub> = 25°C to 150°C; R <sub>GS</sub> = 1 MΩ	1200	V	
V <sub>GS</sub>	Continuous	±30	V	
V <sub>GSM</sub>	Transient	±40	V	
I <sub>D25</sub>	T <sub>C</sub> = 25°C, Chip capability	32	A	
I <sub>DM</sub>	T <sub>C</sub> = 25°C, pulse width limited by T <sub>JM</sub>	128	A	
I <sub>AR</sub>	T <sub>C</sub> = 25°C	32	A	
E <sub>AR</sub>	T <sub>C</sub> = 25°C	64	mJ	
E <sub>AS</sub>	T <sub>C</sub> = 25°C	4	J	
dv/dt	I <sub>S</sub> ≤ I <sub>DM</sub> , di/dt ≤ 100 A/μs, V <sub>DD</sub> ≤ V <sub>DSS</sub> , T <sub>J</sub> ≤ 150°C, R <sub>G</sub> = 2 Ω	15	V/ns	
P <sub>D</sub>	T <sub>C</sub> = 25°C	780	W	
T <sub>J</sub>		-55 ... +150	°C	
T <sub>JM</sub>		150	°C	
T <sub>stg</sub>		-55 ... +150	°C	
V <sub>ISOL</sub>	50/60 Hz, RMS I <sub>ISOL</sub> ≤ 1 mA	t = 1 min 2500 t = 1 s 3000	V~	
M <sub>d</sub>	Mounting torque Terminal connection torque	1.5/13 Nm/lb.in. 1.5/13 Nm/lb.in.		
Weight		30	g	

miniBLOC, SOT-227 B (IXFN)  
 E153432



G = Gate      D = Drain  
 S = Source      TAB = Drain

Either Source terminal at miniBLOC can be used as Main or Kelvin Source

### Features

- International standard package
- miniBLOC, with Aluminium nitride isolation
- Low R<sub>DS(on)</sub> HDMOS™ process
- Rugged polysilicon gate cell structure
- Unclamped Inductive Switching (UIS) rated
- Low package inductance
- Fast intrinsic Rectifier

### Applications

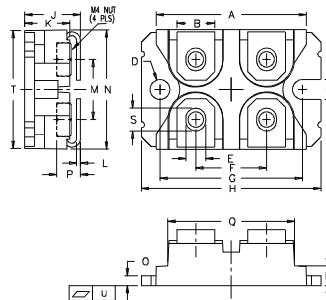
- DC-DC converters
- Battery chargers
- Switched-mode and resonant-mode power supplies
- DC choppers
- Temperature and lighting controls

### Advantages

- Easy to mount
- Space savings
- High power density

Symbol	Test Conditions	Characteristic Values		
		(T <sub>J</sub> = 25°C, unless otherwise specified)	min.	typ.
V <sub>DSS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 3 mA	1200		V
V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 8 mA	2.5		5.0 V
I <sub>GSS</sub>	V <sub>GS(th)</sub> = ±30 V <sub>DC</sub> , V <sub>DS</sub> = 0			±200 nA
I <sub>DSS</sub>	V <sub>DS</sub> = V <sub>DSS</sub> V <sub>GS</sub> = 0 V	T <sub>J</sub> = 25°C T <sub>J</sub> = 125°C		50 μA 3 mA
R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 0.5 • I <sub>D25</sub> Pulse test, t ≤ 300 μs, duty cycle d ≤ 2 %		0.35	Ω

Symbol	Test Conditions	Characteristic Values			
		( $T_J = 25^\circ\text{C}$ , unless otherwise specified)	min.	typ.	max.
$g_{fs}$	$V_{DS} = 20 \text{ V}; I_D = 0.5 \cdot I_{D25}$ , pulse test	28	52	S	
$C_{iss}$ $C_{oss}$ $C_{rss}$	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$	15900		pF	
		1000		pF	
		260		pF	
$t_{d(on)}$ $t_r$ $t_{d(off)}$ $t_f$	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \cdot V_{DSS}, I_D = 0.5 \cdot I_{D25}$ $R_G = 1 \Omega$ (External),	36		ns	
		42		ns	
		98		ns	
		22		ns	
$Q_{g(on)}$ $Q_{gs}$ $Q_{gd}$	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \cdot V_{DSS}, I_D = 0.5 \cdot I_{D25}$	400		nC	
		70		nC	
		188		nC	
$R_{thJC}$			0.16	K/W	
$R_{thCK}$			0.05	K/W	

**miniBLOC, SOT-227 B**


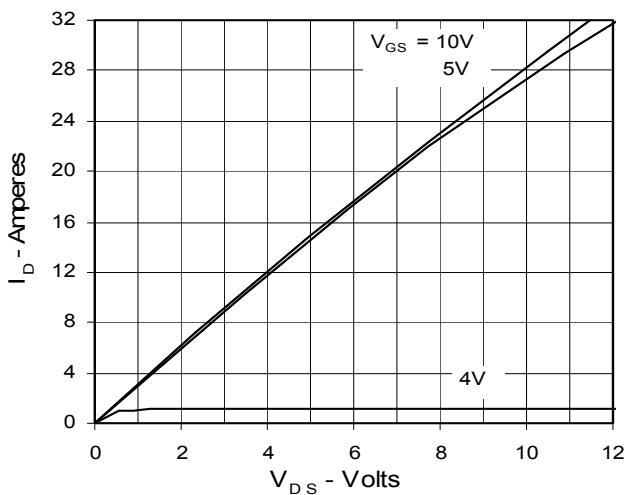
M4 screws (4x) supplied

Dim.	Millimeter		Inches	
	Min.	Max.	Min.	Max.
A	31.50	31.88	1.240	1.255
B	7.80	8.20	0.307	0.323
C	4.09	4.29	0.161	0.169
D	4.09	4.29	0.161	0.169
E	4.09	4.29	0.161	0.169
F	14.91	15.11	0.587	0.595
G	30.12	30.30	1.186	1.193
H	38.00	38.23	1.496	1.505
J	11.68	12.22	0.460	0.481
K	8.92	9.60	0.351	0.378
L	0.76	0.84	0.030	0.033
M	12.60	12.85	0.496	0.506
N	25.15	25.42	0.990	1.001
O	1.98	2.13	0.078	0.084
P	4.95	5.97	0.195	0.235
Q	26.54	26.90	1.045	1.059
R	3.94	4.42	0.155	0.174
S	4.72	4.85	0.186	0.191
T	24.59	25.07	0.968	0.987
U	-0.05	0.1	-0.002	0.004

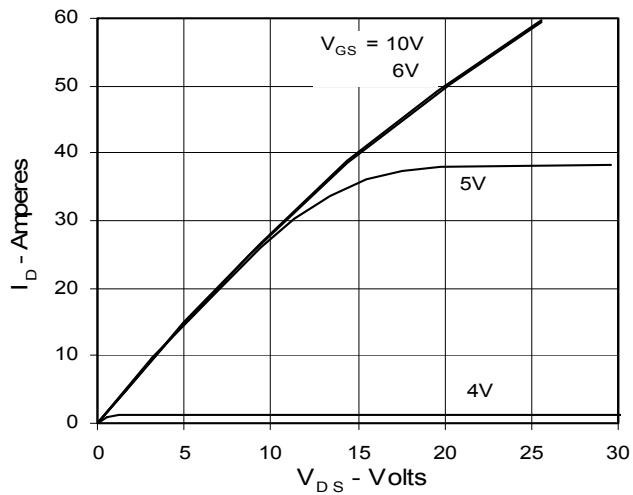
**Source-Drain Diode**
**Characteristic Values**  
 $(T_J = 25^\circ\text{C}$ , unless otherwise specified)

Symbol	Test Conditions	min.	typ.	max.
$I_s$	$V_{GS} = 0 \text{ V}$		32	A
$I_{SM}$	Repetitive; pulse width limited by $T_{JM}$		128	A
$V_{SD}$	$I_F = I_s, V_{GS} = 0 \text{ V}$ , Pulse test, $t \leq 300 \mu\text{s}$ , duty cycle $d \leq 2 \%$		1.3	V
$t_{rr}$ $Q_{RM}$ $I_{RM}$	$I_F = 25 \text{ A}$ , $-\text{di}/\text{dt} = 100 \text{ A}/\mu\text{s}$ , $V_R = 100 \text{ V}$	180 1.4 8	300	ns $\mu\text{C}$ A

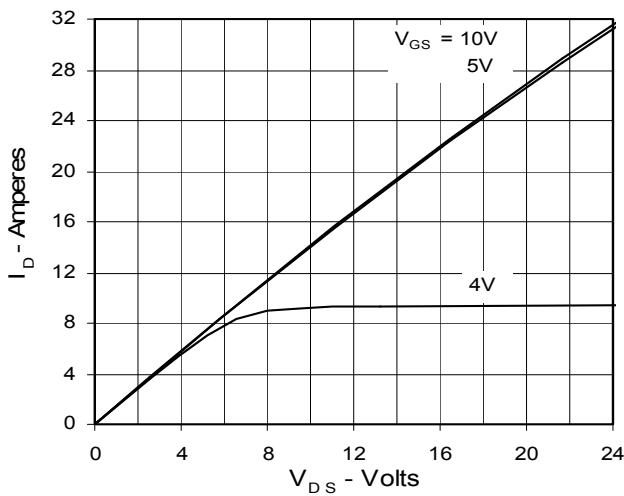
**Fig. 1. Output Characteristics  
@ 25 Deg. C**



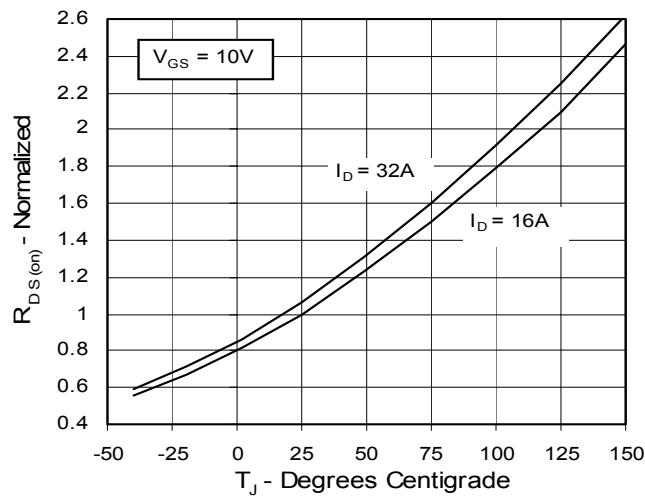
**Fig. 2. Extended Output Characteristics  
@ 25 deg. C**



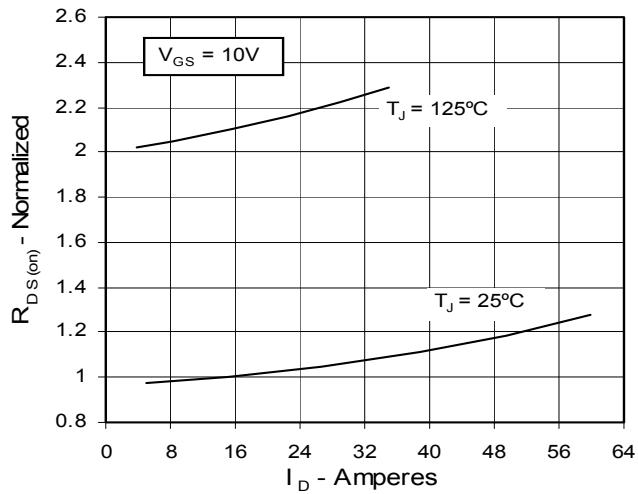
**Fig. 3. Output Characteristics  
@ 125 Deg. C**



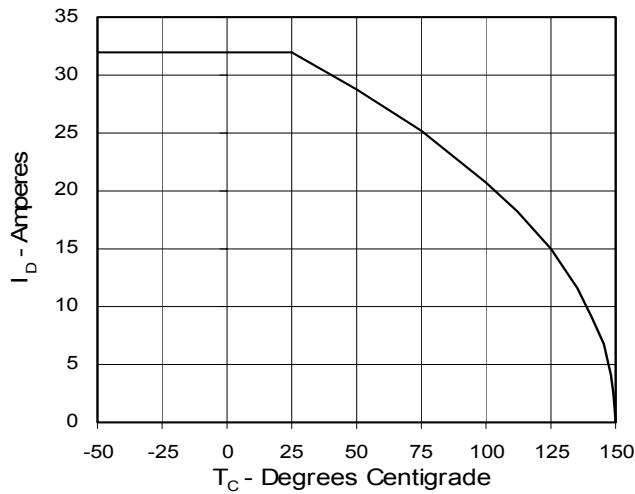
**Fig. 4.  $R_{DS(on)}$  Normalized to  $I_{D25}$  Value vs.  
Junction Temperature**



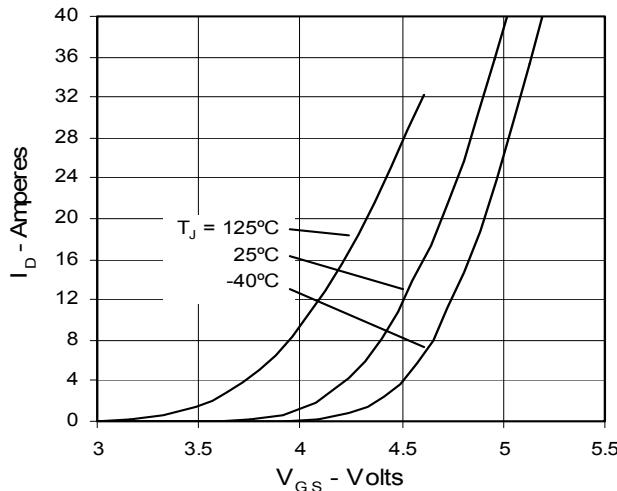
**Fig. 5.  $R_{DS(on)}$  Normalized to  $I_{D25}$   
Value vs.  $I_D$**



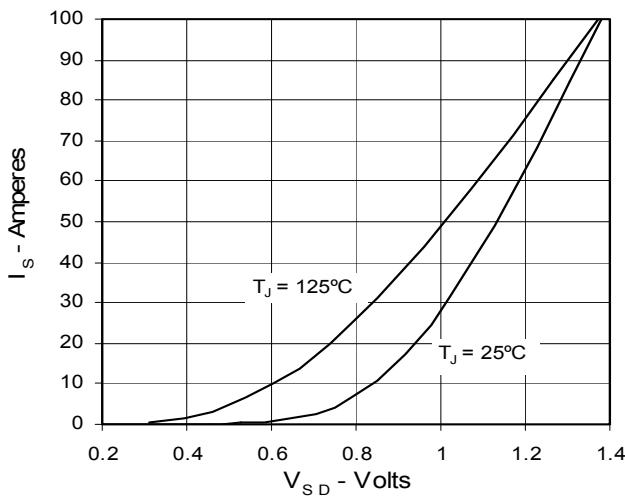
**Fig. 6. Drain Current vs. Case  
Temperature**



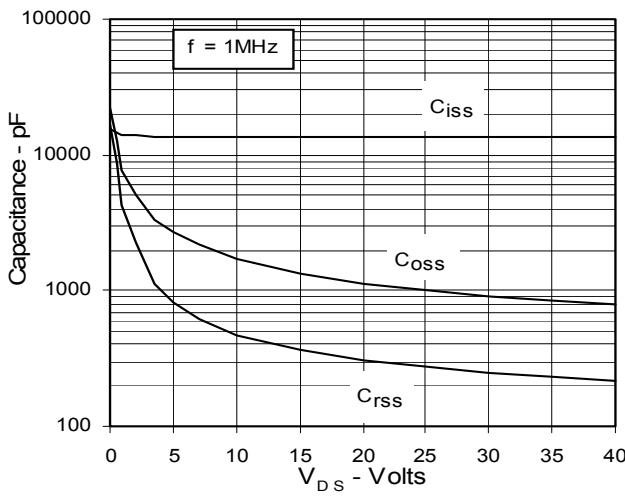
**Fig. 7. Input Admittance**



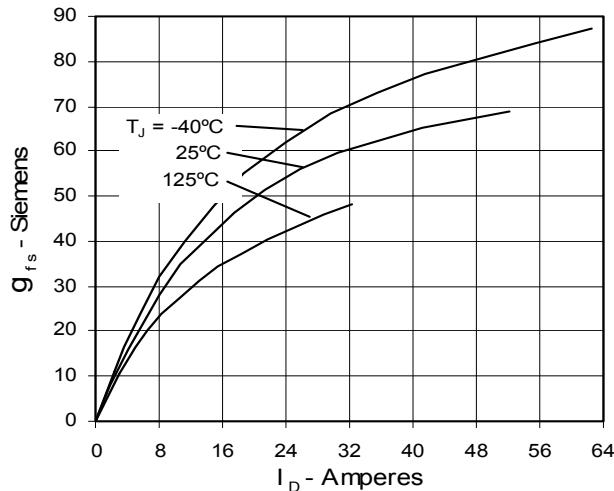
**Fig. 9. Source Current vs.  
Source-To-Drain Voltage**



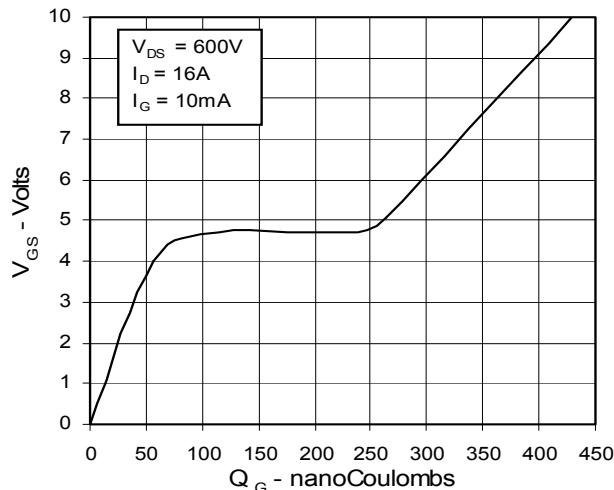
**Fig. 11. Capacitance**



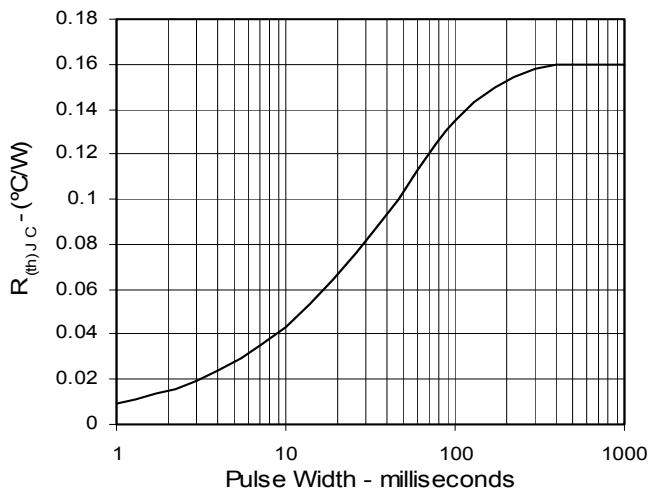
**Fig. 8. Transconductance**



**Fig. 10. Gate Charge**



**Fig. 12. Maximum Transient Thermal Resistance**



IXYS reserves the right to change limits, test conditions, and dimensions.

IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents:

4,835,592 4,881,106 5,017,508 5,049,961 5,187,117 5,486,715 6,306,728B1 6,259,123B1 6,306,728B1  
4,850,072 4,931,844 5,034,796 5,063,307 5,237,481 5,381,025 6,404,065B1 6,162,665 6,534,343